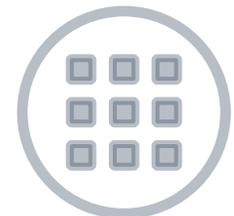




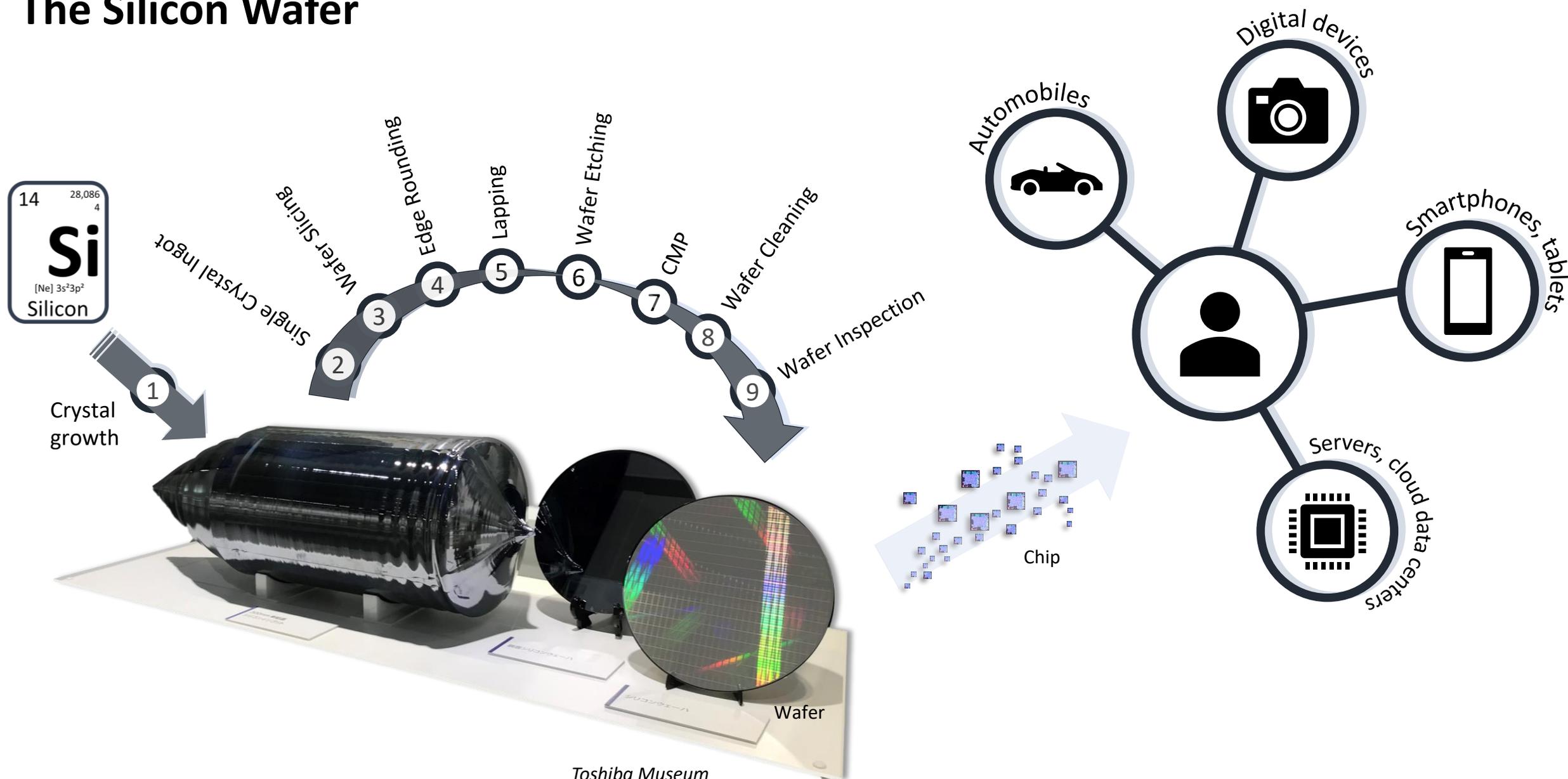
# CHALLENGES FOR HIGH-FREQUENCY ULTRASONIC CLEANING SYSTEMS

EUROPEAN CMP USERS MEETING

NOVEMBER 2022



# The Silicon Wafer





# KAIJO CORPORATION

**KAIJO** is a manufacturer of ultrasonic cleaning equipment.

**Established** : July 21, 1948

**Location** : Tokyo, Hamura-city (Headquarters)  
Nagano, Matsumoto-city (Factory)

**Employees** : 293 (2022)

**Paid-in Capital** : JPY90M (USD\$0.82M)

**Parent Company** : Shibuya Corporation

**Main Business** : Semiconductor Assembling Equipment,  
Ultrasonic Cleaning Equipment,  
OEM/ODM business.

**Kaijo Shibuya Europe (KSE)** : Wiesbaden, Germany  
(Established in October 2018)



# Ultrasonic Cleaning Equipment

- Specialized equipment for wafer cleaning after the polishing process

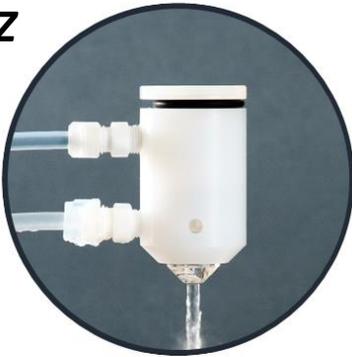
**KAIJO**

Supplies ultrasonic cleaning tools to  
CMP equipment manufacturers



CMP Equipment  
Maker, Japan

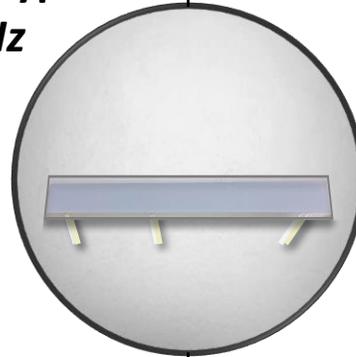
Shower Type  
950kHz



Worldwide Market

CMP Equipment  
Maker, USA

Plate Type  
950kHz



Worldwide Market

CMP Equipment  
Makers, China

China Market

# Ultrasonic Cleaning Equipment

- Specialized equipment for wafer cleaning after the polishing process

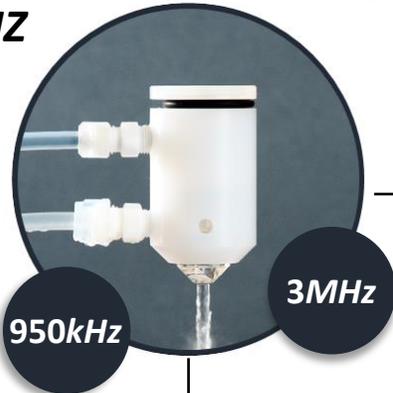
**KAIJO**

Supplies ultrasonic cleaning tools to  
CMP equipment manufacturers



CMP Equipment  
Maker, Japan

Shower Type  
950kHz



Worldwide Market

## KAIJO QUAVA SPOT Shower

- Ultrasonic Cleaning Tool for a Single Wafer



30110 (QT-029CE)

Ultrasonic Generator

The ultrasonic energy passing through the  
DI water detaches the particles adhering at  
the wafer surface.

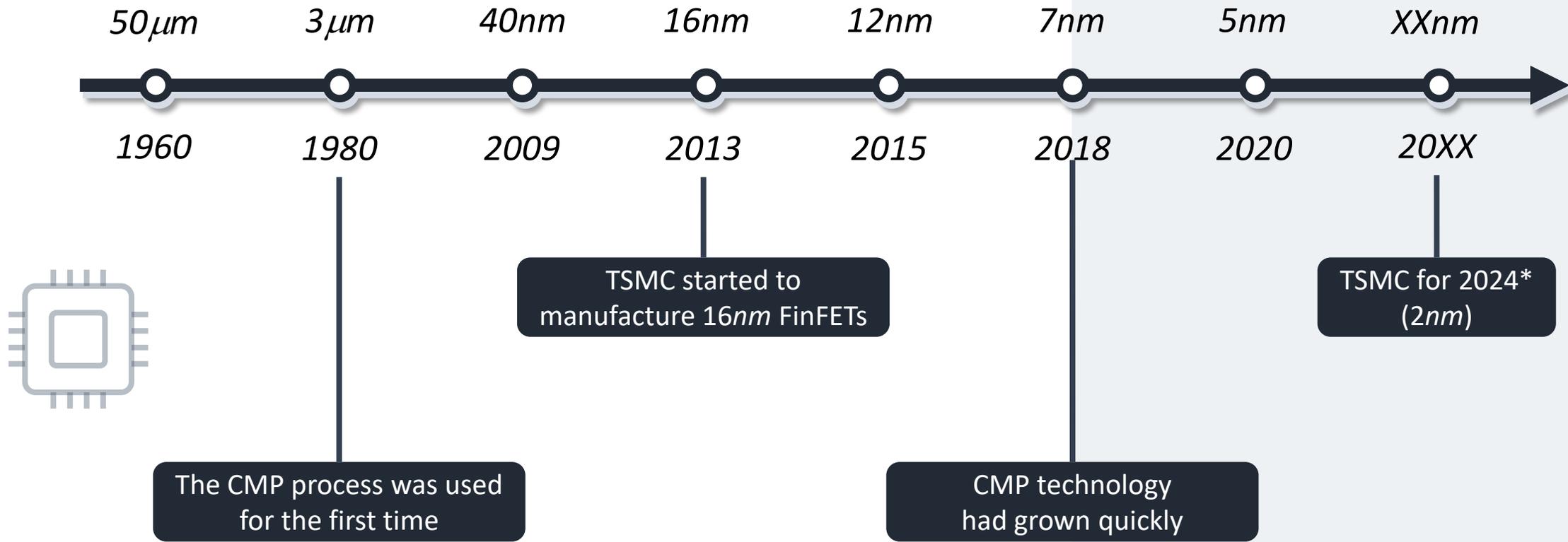


QUAVA SPOT Shower Transducer

# Technology Node Timeline

- Semiconductor lithography processes technology

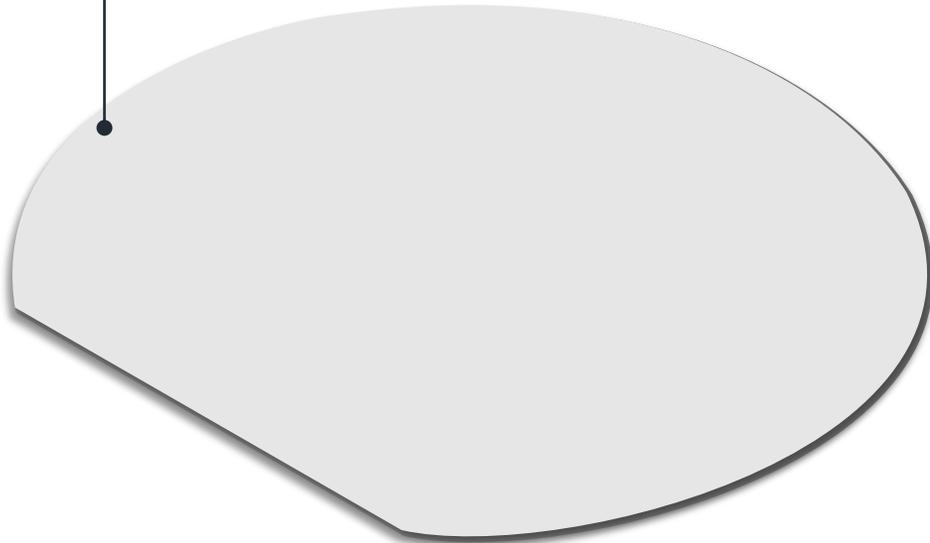
- A more rigorous cleaning process is required from 7nm node



# Silicon Wafer Particle Removal



① Wafer



- CMP-induced defects caused by residual particles, foreign materials, scratches, corrosion, etc.
- Cleaning after CMP has become a crucial step in the process of wafer manufacturing to minimize defects such as residual particles, foreign materials, scratches and corrosion.
- Defects generated after the CMP process, especially particles on the wafer surface, can be removed with Megasonic cleaning.
- Megasonic cleaning removes particles on the wafer surface more effectively than chemical methods.

No defect  
generation



High-quality  
wafer output

# Ultrasonic Wafer Cleaning by Spot Shower

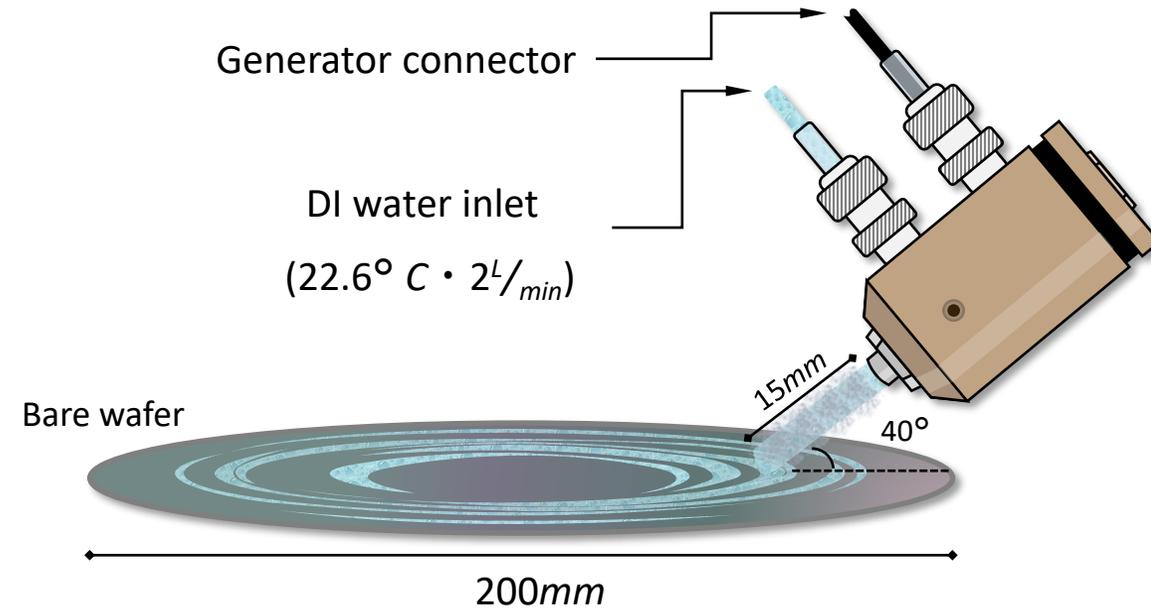
## Equipment used

- QUAVA SPOT Shower Transducer.
- Ultrasonic output power of 30W.
- Working frequency of 950KHz and 3MHz.

## Ultrasonic cleaning conditions

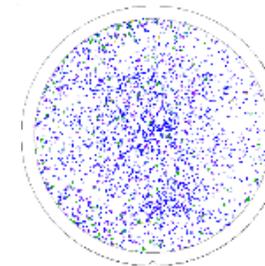
- Ultrasonic cleaning of bare wafer.
- Particles to be removed  $\text{SiO}_2$  ( $\geq 80\text{nm}$ ).
- Wafer spinning of 400rpm.
- DI water as cleaning liquid ( $2\text{L}/\text{min}$ ).
- Cleaning time of 30s (6 sets of 5s).

## Ultrasonic cleaning scheme

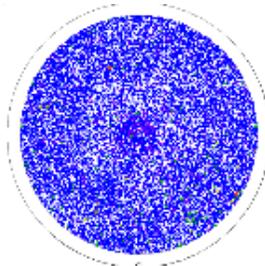


## Ultrasonic cleaning results (MAP)

SPOT Shower  
950kHz/30W  
PRE of 90.4%



SPOT Shower  
3MHz/30W  
PRE of 24.5%



## Particle Removal Efficiency

$$PRE(\%) = \frac{n_i - n_f}{n_i} \times 100$$

where

$n$  = Number of particles

$n_i = n_{\text{After adding SiO}_2} - n_{\text{Before adding SiO}_2}$

$n_f = n_{\text{After ultrasonic cleaning}} - n_{\text{Before adding SiO}_2}$



# New Spot Shower Design

Parabolic Reflexional High Power (PRHP)  
Ultrasonic Transducer



Coming soon!

- Designed for high frequency cleaning
- High sound pressure
- Damage reduction

Challenge to efficiently remove nanoparticles  
without damaging the wafer surface



# Ultrasonic Wafer Cleaning by PRHP

## Equipment used

- Parabolic Reflexional High Power Transducer.
- Ultrasonic output power of 34.1W.
- Working frequency of 1.5MHz.

## Ultrasonic cleaning conditions

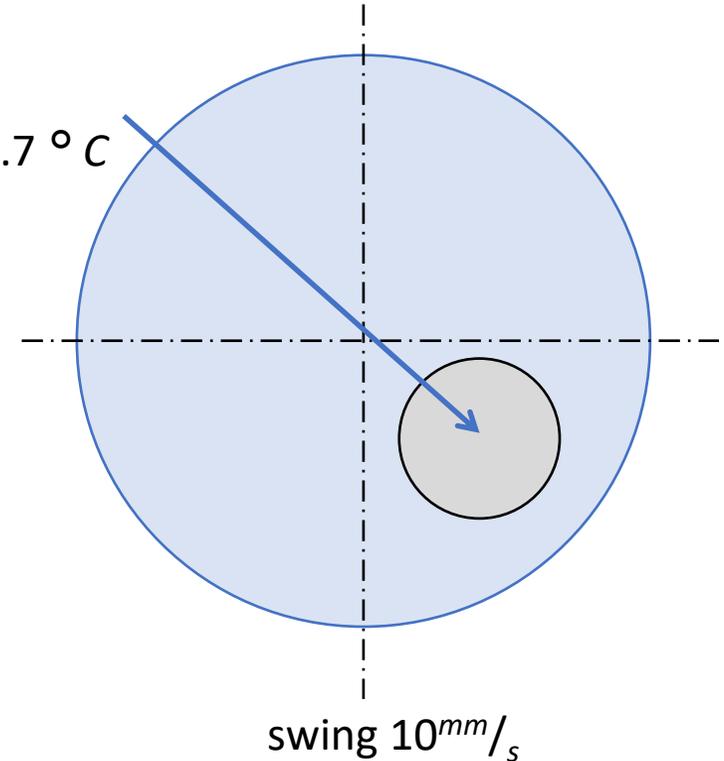
- Ultrasonic cleaning of bare wafer.
- Wafer spin of 60rpm.
- DI water as cleaning liquid (1L/min).
- Cleaning time of 60s (6 sets of 10s).

DIW

Flow : 1L/min

Temperature : 23.7 °C

DO: 6.88mg/L



## Particle Removal Efficiency

$$PRE(\%) = \frac{n_i - n_f}{n_i} \times 100$$

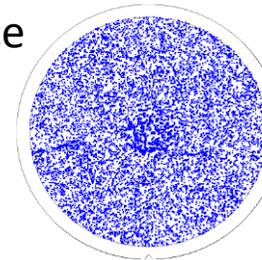
where

$n$  = Number of particles

$n_i = n_{\text{After adding SiO}_2} - n_{\text{Before adding SiO}_2}$

$n_f = n_{\text{After ultrasonic cleaning}} - n_{\text{Before adding SiO}_2}$

Reference  
Before  
Cleaning



PRHP  
1.5MHz/34.1W  
PRE of 37%



# New Spot Shower development schedule



## September 2022

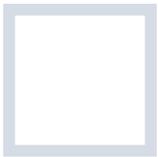
Complete preliminary tests and determine the basic construction of the transducer.

## December 2022

Finalize the design of the transducer unit.

## March 2023

Complete development and accumulate evaluation data for sales promotion.





**Thank you for  
your attention**